

Supplementary Information

Solvothermal and mechanochemical intercalation of Cu into $\text{La}_2\text{O}_2\text{S}_2$ enabled by the redox reactivity of $(\text{S}_2)^{2-}$ pairs

Experimental procedures

1. X-ray diffraction

Powder X-ray diffraction (XRD) patterns were recorded at room temperature on a Bruker D8 Advance Diffractometer (Bragg-Brentano geometry, θ - 2θ), which employs Cu $K_{\alpha 1}$ radiation ($\lambda = 1.540598 \text{ \AA}$) produced through Ge (111) monochromator and LynxEye detector.

2. 3D electron diffraction analyses

The brown powder obtained after solid-solid reaction between 2.0 eq. of Cu and $\text{La}_2\text{O}_2\text{S}_2$ was used for TEM analyses. The powder sample was dispersed in ethanol and a drop of the suspension was deposited and dried on a copper grid with a thin film of holey amorphous carbon. 3D electron diffraction (3D ED) data sets^{1,2} were collected with the precession electron diffraction tomography (PEDT) technique³⁻⁶ on a Philips CM120 electron transmission microscope (TEM) ($V_{\text{acc}}=120 \text{ kV}$, LaB_6) coupled with the precession device Nanomegas Digistar and a side-mounted CCD camera Olympus Veleta with 14-bit dynamic range. Non-oriented patterns were recorded stepwise at the ambient temperature on 2 nanocrystals (Fig. 3) with $\sim 200 \text{ nm}$ diameter. The precession angle was set to 1 degree with a tilt step of 1 degree. A condenser aperture of $10 \text{ }\mu\text{m}$ and low illumination setting (spot size 7) were used to preserve the crystal during the data collection. PEDT data were analyzed using the computer programs PETS2.0⁷ and JANA2006.⁸ For each data set, two lists of hkl -indices with associated intensities and estimated standard deviations are obtained: one for the structure solution and another one for the dynamical refinement. We adopted the parameters suggested by Palatinus et al.⁹⁻¹⁰ to select reflections involved in the dynamic refinement: $RSg(\text{max}) = 0.65$, $Sg(\text{max}) (\text{matrix}) = 0.01 \text{ \AA}^{-1}$ and $g(\text{max}) = 1.7 \text{ \AA}^{-1}$.

Results

1. 3D electron diffraction analyses

The analysis of the PEDT data gives a tetragonal unit-cell with $a \approx 4.01(1)$ Å, and $c \approx 8.46(6)$ Å that is consistent with our previous Rietveld refinement for the intercalated phase ($a = 3.9982(5)$ Å and $c = 8.5125(3)$ Å)¹³ as well as the powder sample prepared by high-temperature synthesis at $T = 800$ °C ($a = 3.99625(5)$ Å and $c = 8.51743(9)$ Å).¹¹ The space group $P4/nmm$ is compatible with the sections of the reciprocal space (Fig. S1). The model was solved in JANA2006 using the charge flipping algorithm in the program Superflip.¹² Two data sets were combined to reach 90% coverage (for $\theta = 1.34$ deg) in the $P4/nmm$ space group with 119/125 observed over all independent reflections (averaged from the 1625/1792 measured). The refined atomic positions for lanthanum $z/c = 0.1439(3)$ and sulfur $z/c = 0.6729(1)$, which are comparable to our previous refinement based on XRD data ($z/c = 0.1473(2)$ and $z/c = 0.6627(4)$ for lanthanum and sulfur, respectively).

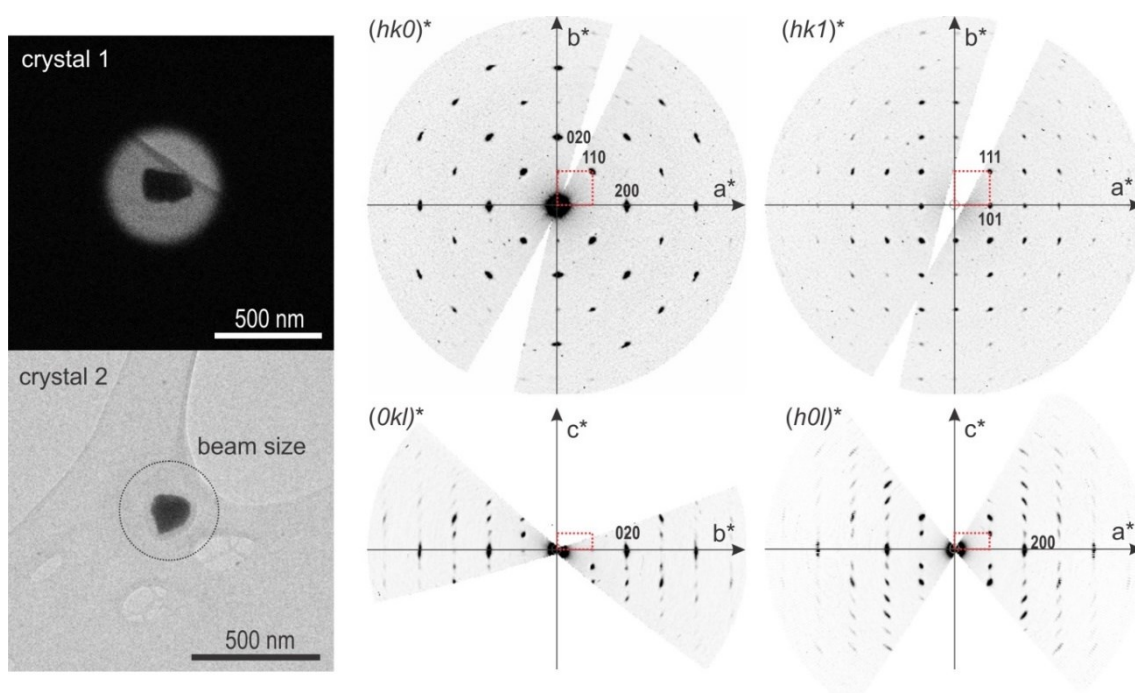


Fig. S1. From the left to the right, picture of the two $\text{La}_2\text{O}_2\text{Cu}_2\text{S}_2$ crystals used in the structural characterization and sections of the reciprocal space reconstructed in PETS2.0. The unit-cell is represented in red.

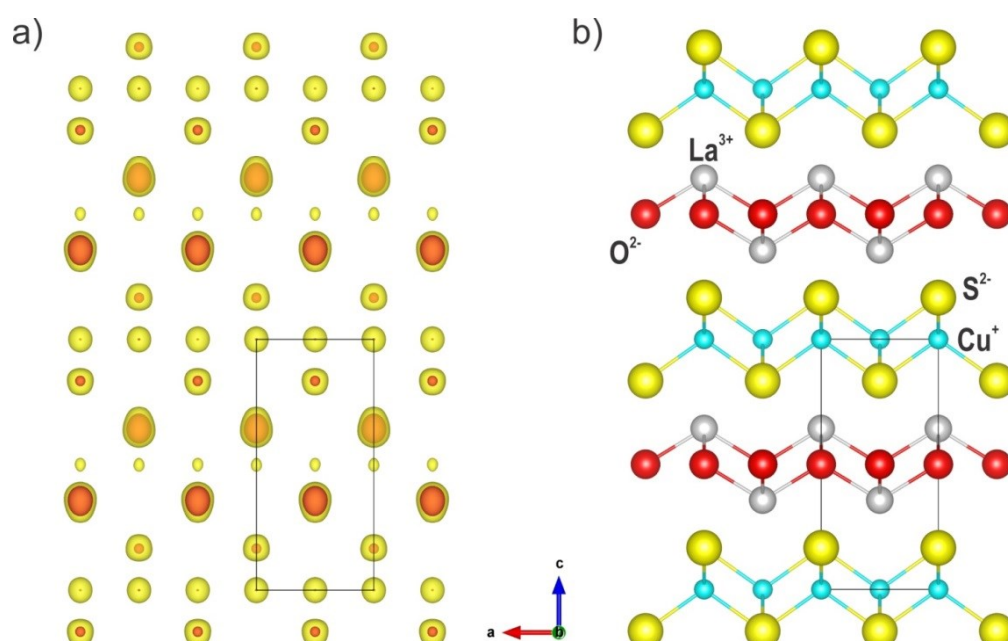


Fig. S2. (a) Projection along b of the 3D electrostatic potential map (direct solution) and, (b) corresponding model for $\text{La}_2\text{O}_2\text{Cu}_2\text{S}_2$.

Table S1. Summary of PEDT data collection conditions and refinement parameters for $\text{La}_2\text{O}_2\text{Cu}_2\text{S}_2$.

Structural formula	$\text{La}_2\text{O}_2\text{Cu}_2\text{S}_2$
Unit-cell parameters (RXPd)	$a = 3.9982(5) \text{ \AA}$, $c = 8.5125(3) \text{ \AA}$
V	$136.08(1) \text{ \AA}^3$
Z	1
Space group	$P4/nmm$
$d_{\text{calc}} (\text{g} \cdot \text{cm}^{-3})$	6.1139 (for the formula given above)
Temperature	ambient T
Diffractometer	TEM Philips CM120
Radiation (wavelength)	electrons, (0.0335 \AA)
Resolution	$0.1\text{--}0.7 \text{ \AA}^{-1}$
Limiting Miller indices	$0 \leq h \leq 3$, $1 \leq k \leq 5$, $0 \leq l \leq 11$
Coverage	90%
No. of independent reflections (obs/all) – kinematic	119/125
R_{int} (obs/all) – kinematic	0.1674/0.2164
Redundancy	12.237
----- Dynamical refinement by Jana2006:	
Reflection selection parameter	$\text{RS}_g(\text{max}) = 0.65$
No. of reflections (obs/all)	2339/2905
R , wR (obs)	0.1261/0.1451
N parameters/ N struct. parameters	201/6

Table S2. Atom positions, displacement parameters (equivalent/isotropic, in Å²) for the crystal structure of La₂O₂Cu₂S₂.

Atom	Wyck.	<i>x/a</i>	<i>y/b</i>	<i>z/c</i>	Occ.	<i>U</i> _{iso} (Å ²)
La1	2c	0	0.5	0.1439(3)	1	0.0100(5)
Cu1	2b	0	0	0.5	1	0.0332(10)
S1	2c	0	0.5	0.6729(11)	1	0.0274(11)
O1	2a	0	0	0	1	0.0043(13)
distances	Cu1-S1:	2.482(6) Å,	La1-O1:	2.345(1) Å,	O1-O1:	2.8272 Å

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